

INTERNATIONAL STANDARD



**Semiconductor devices –
Part 5-11: Optoelectronic devices – Light emitting diodes – Test method of
radiative and nonradiative currents of light emitting diodes**

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SEMICONDUCTOR DEVICES –

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Full information on the voting for the approval of this International Standard can be found in the report on voting indicated in the above table.

This document has been drafted in accordance with the ISO/IEC Directives, Part 2.

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Future standards in this series will carry the new general title as cited above. Titles of existing standards in this series will be updated at the time of the next edition.

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SEMICONDUCTOR DEVICES –

Part 5-11: Optoelectronic devices – Light emitting diodes – Test method of radiative and nonradiative currents of light emitting diodes

1 Scope

This part of IEC 60747 specifies the measuring methods of radiative and nonradiative currents of single light emitting diode (LED) chips or packages without phosphor. White LEDs for lighting applications are out of the scope of this document. This document utilizes the internal quantum efficiency (IQE) as a function of current, whose measurement methods are discussed in other documents.

2 Normative references

The following documents are referred to in the text in such a way that some or all of their content constitutes requirements of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

IEC 60747-5-6:2016, *Semiconductor devices – Part 5-6: Optoelectronic devices – Light emitting diodes*